IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Tatsuhiko HATANO et al.

Application No.: New U.S. National Stage of PCT/JP2004/017099

Filed: May 16, 2006 Docket No.: 128029

For: HIGH VOLTAGE PULSE GENERATING CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of one or more non-English language reference is discussed in the present specification. See References 17 & 26.
- 3. One or more reference cited herein was cited in the International Search Report.
 An English language version of the International Search Report is attached for the Examiner's information. See References 16 & 24-25.
- 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- 5. A partial English language Translation of one or more non-English language reference is attached hereto. See Reference 30.
- 6. An English language Abstract of one or more non-English language reference is attached hereto. See References 16-17, 20-22 & 24-26.
- 7. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy. See References 16-17 & 20-25.

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8. One or more co-pending U.S. patent application is identified on the attached Form PTO 1449. The Examiner is respectfully requested to consider each cited application and the art cited therein during examination of the present application.

9. Reference 1 corresponds to reference 16. Reference 12 corresponds to reference 24.

James A. Oliff

Registration No. 27,075

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JAO:DAT/nxy

Date: May 16, 2006

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE
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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128029		APPLICATION NO. New U.S. Patient Application		
INFORMATION DISCLOSURE STATEMENT					•	Application		
(Use several sheets if necessary)				APPLICANTS Tatsuhiko HATANO et al.				
				FILING DATE May 16, 2006			-	
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Examiner Initials	Cite (Including Author, Title, Date, Pertinent Pages, etc.) No.							
EXAMINER /Rajnikant Patel/ (02/26/2008) DATE CONSIDERED								
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Date: May 16, 2006

US Dept. of Commerce ATTY DOCKET NO. APPLICATION NO. Form PTO-1449 New U.S. Patent PATENT & TRADEMARK OFFICE 128029 (REV. 1/06) Application INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary) **APPLICANTS** Tatsuhiko HATANO et al. FILING DATE May 16, 2006 U.S. PATENT DOCUMENTS Examiner Cite Date Initials No. Document Number Name FOREIGN PATENT DOCUMENTS Cite With With Examiner Initials No. Document Number Date Country English English Translation Abstract /RP/ 17. JP-A-2002-044965 02/08/2002 **JAPAN** X Х /RP/ 18. EP 0 959 562 A1 11/24/1999 **EUROPE** 7RP. 03/30/1983 UNITED KINGDOM 19. GB 2 105 927 A JP-A-2003-272887 09/26/2003 X Х 20. JAPAN /RP /RP/ JP-A-10-76182 03/24/1998 **JAPAN** Х x 21. /RP/ 22. JP-A-11-145793 05/28/1999 **JAPAN** Х Х /RP/ JP-B2-2649340 05/16/1997 Х 23. **JAPAN** /RP/ JP-A-08-223915 08/30/1996 **JAPAN** Х Х 24. /RP 25. JP-A-2003-338648 11/28/2003 **JAPAN** X Х OTHER DOCUMENTS Examiner Cite (Including Author, Title, Date, Pertinent Pages, etc.) Initials No. IIDA et al., "Ultra Short-width High-Voltage Pulse Generator"; The Institute of Electrical Engineers of Japan; Plasma 26. /RP/ Science and Technology, Dept. of Manufacturing Engineering NGK Insulators, Ltd.; Lecture No. PST-02-16.(w/ abstract) 27. JIANG et al., "Compact, High Repetition-Rate Pulsed Power Generator Using High-Speed Si-Thyristor"; IEEE; pp. 602-/RP/ 604; June 30, 2002; Conference Record of the 25th International Power Modulator Symposium and 2002 High-Voltage Workshop: July 30-July 3, 2002. YAMASHITA et al., "High Rep-Rate Inductive-Energy-Storage Pulsed Power Modulator Using High Voltage Static 28. /RP/ Induction Thyristor"; IEEE; pp. 382-385; June 30, 2002; Conference Record of the 25th International Power Modulator Symposium and 2002 High-Voltage Workshop: June 30-July 3 2002. **EXAMINER** DATE CONSIDERED /Rajnikant Patel/ (02/26/2008) Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance Examiner: and not considered. Include copy of this form with next communication to applicant.

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